

INFORMATION DISCLOSURE CITATION			ATTORNEY'S DKT NO. 007325-077	APPLICATION NO. Unassigned		
PTO-1449			APPLICANT Frank J. KOCH et al.			
			FILING DATE September 15, 1995	GROUP Unassigned		
U.S. & TRADEMARK DOCUMENTS						
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS		
<i>WEN</i>	4,695,797	09-1987	DEUTSCH ET AL.	324		
				230		
FOREIGN PATENT DOCUMENTS						
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation Yes No
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)						
<i>WEN</i>	Verax Systems, Inc.; SPC FocusPLUS; 1993; 9 pages;					
<i>WEN</i>	Introductory Pages of User's Manual for SPC FocusPLUS; Verax Systems, Inc.; 1994; 15 pages.					
<i>WEN</i>	SPC FocusPLUS User's Manual; Chapter 6; Variables Data Collection; 28 pages.					
<i>WEN</i>	Interface between Elcometer...; Instruction Sheet; pages 4316-1 through 4316-3.					
<i>WEN</i>	Elcometer 500 Literature; elcometer 500; 8 pages; 1986.					
<i>WEN</i>	Elcometer 500; Instruction Manual; Publication ELC0500/0886/3.05; 55 pages;					
<i>WEN</i>	Leptoskop Layer Thickness Gauges; 4 pages					
<i>WEN</i>	NDTnet; Karl Deutsch Handterminal 2051 Layer Thickness Measuring with or without PC; October 1998; 1 page.					
<i>WEN</i>	Sonden für LEPTOSKOP 2040 in Orginalgrüße; 1995; 1 page.					
EXAMINER	<i>WEN</i>		DATE CONSIDERED	12/8/09 <i>6/1/00</i>		

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.